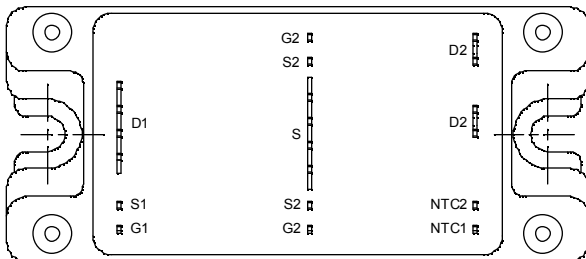
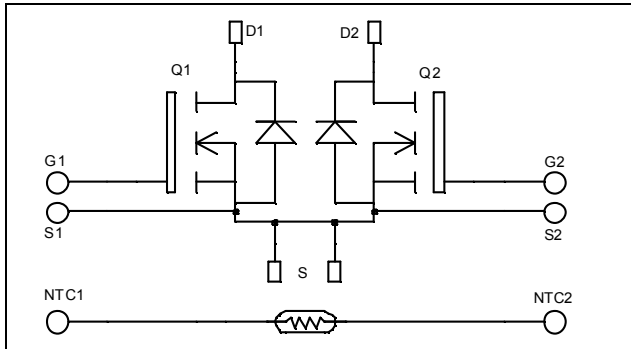


Dual common source MOSFET Power Module

$V_{DSS} = 500V$
 $R_{DSon} = 35m\Omega \text{ typ @ } T_j = 25^\circ C$
 $I_D = 99A \text{ @ } T_c = 25^\circ C$



Application

- AC Switches
- Switched Mode Power Supplies
- Uninterruptible Power Supplies

Features


- Power MOS 7[®] MOSFETs
 - Low R_{DSon}
 - Low input and Miller capacitance
 - Low gate charge
 - Avalanche energy rated
 - Very rugged
- Kelvin source for easy drive
- Very low stray inductance
 - Symmetrical design
 - Lead frames for power connections
- Internal thermistor for temperature monitoring
- High level of integration

Benefits

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

Absolute maximum ratings

Symbol	Parameter	Max ratings	Unit
V_{DSS}	Drain - Source Breakdown Voltage	500	V
I_D	Continuous Drain Current	$T_c = 25^\circ C$	99
		$T_c = 80^\circ C$	74
I_{DM}	Pulsed Drain current	396	
V_{GS}	Gate - Source Voltage	± 30	V
R_{DSon}	Drain - Source ON Resistance	39	$m\Omega$
P_D	Maximum Power Dissipation	$T_c = 25^\circ C$	781
I_{AR}	Avalanche current (repetitive and non repetitive)	51	A
E_{AR}	Repetitive Avalanche Energy	50	mJ
E_{AS}	Single Pulse Avalanche Energy	3000	


CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com

All ratings @ $T_j = 25^\circ\text{C}$ unless otherwise specified

Electrical Characteristics

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0\text{V}, V_{DS} = 500\text{V}$			200	μA
		$V_{GS} = 0\text{V}, V_{DS} = 400\text{V}$			1000	
$R_{DS(on)}$	Drain – Source on Resistance	$V_{GS} = 10\text{V}, I_D = 49.5\text{A}$		35	39	$\text{m}\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 5\text{mA}$	3		5	V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 30\text{V}, V_{DS} = 0\text{V}$			± 150	nA

Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}$		14		nF
C_{oss}	Output Capacitance	$V_{DS} = 25\text{V}$		2.8		
C_{rss}	Reverse Transfer Capacitance	$f = 1\text{MHz}$		0.2		
Q_g	Total gate charge	$V_{GS} = 10\text{V}$		280		nC
Q_{gs}	Gate – Source Charge	$V_{Bus} = 250\text{V}$		80		
Q_{gd}	Gate – Drain Charge	$I_D = 99\text{A}$		140		
$T_{d(on)}$	Turn-on Delay Time	Inductive switching @ 125°C $V_{GS} = 15\text{V}$ $V_{Bus} = 333\text{V}$ $I_D = 99\text{A}$ $R_G = 1\Omega$		21		ns
T_r	Rise Time			38		
$T_{d(off)}$	Turn-off Delay Time			75		
T_f	Fall Time			93		
E_{on}	Turn-on Switching Energy	Inductive switching @ 25°C $V_{GS} = 15\text{V}, V_{Bus} = 333\text{V}$ $I_D = 99\text{A}, R_G = 1\Omega$		2070		μJ
E_{off}	Turn-off Switching Energy			1690		
E_{on}	Turn-on Switching Energy	Inductive switching @ 125°C $V_{GS} = 15\text{V}, V_{Bus} = 333\text{V}$ $I_D = 99\text{A}, R_G = 1\Omega$		3112		μJ
E_{off}	Turn-off Switching Energy			2026		

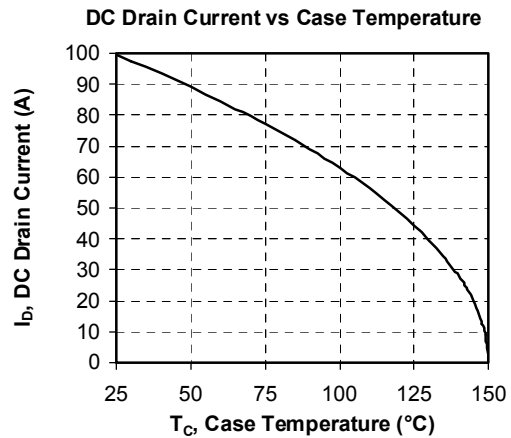
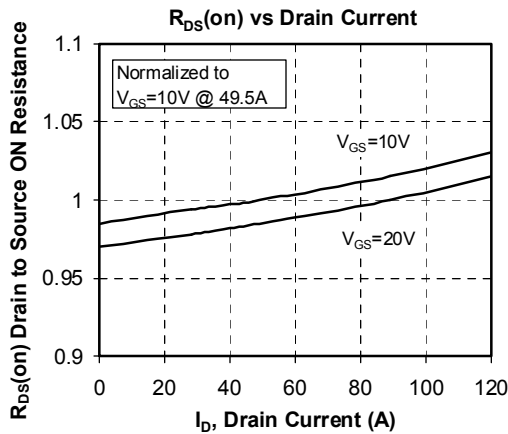
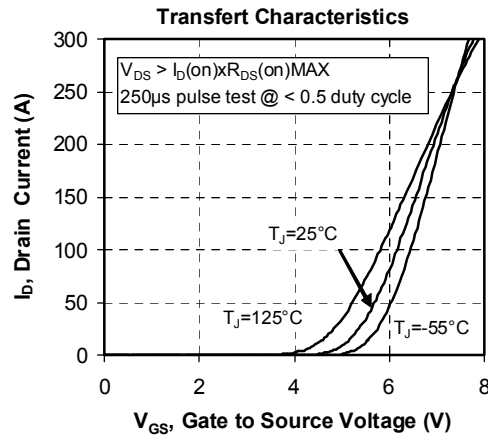
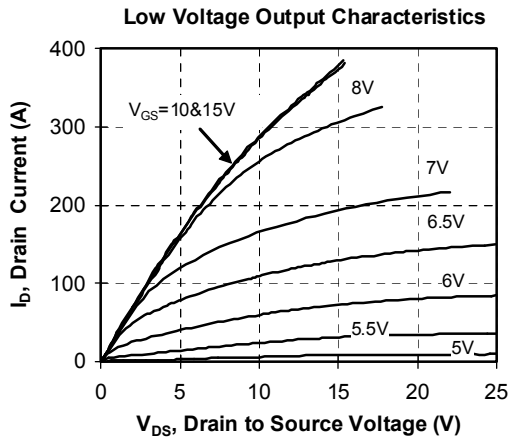
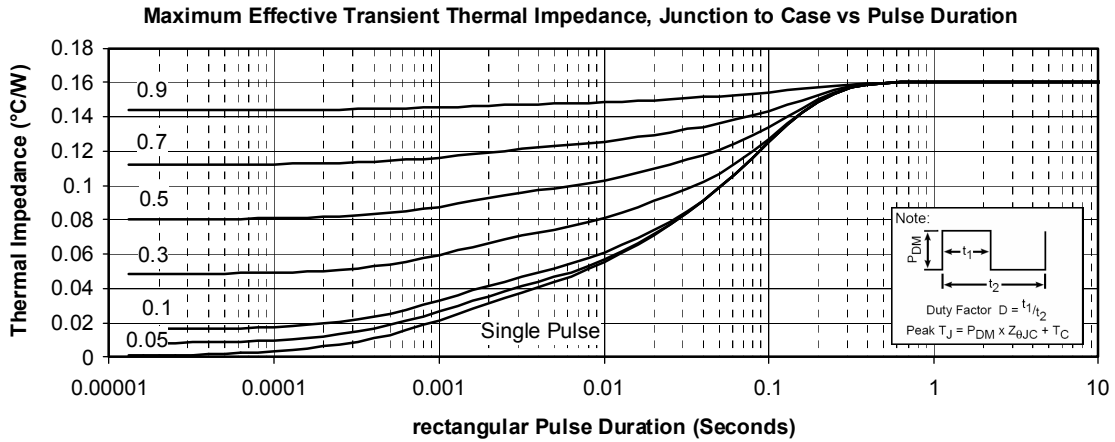
Source - Drain diode ratings and characteristics

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I_S	Continuous Source current (Body diode)	$T_c = 25^\circ\text{C}$			99	A
		$T_c = 80^\circ\text{C}$			74	
V_{SD}	Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = -99\text{A}$			1.3	V
dv/dt	Peak Diode Recovery ^①				8	V/ns
t_{rr}	Reverse Recovery Time	$I_S = -99\text{A}, V_R = 333\text{V}$		680		ns
Q_{rr}	Reverse Recovery Charge	$di_s/dt = 200\text{A}/\mu\text{s}$		34		μC

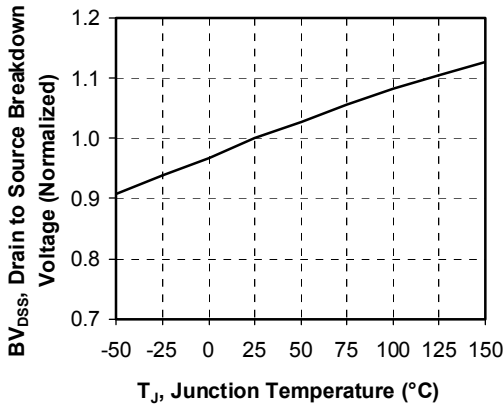
^① dv/dt numbers reflect the limitations of the circuit rather than the device itself.

$$I_S \leq -99\text{A} \quad di/dt \leq 700\text{A}/\mu\text{s} \quad V_R \leq V_{DSS} \quad T_j \leq 150^\circ\text{C}$$

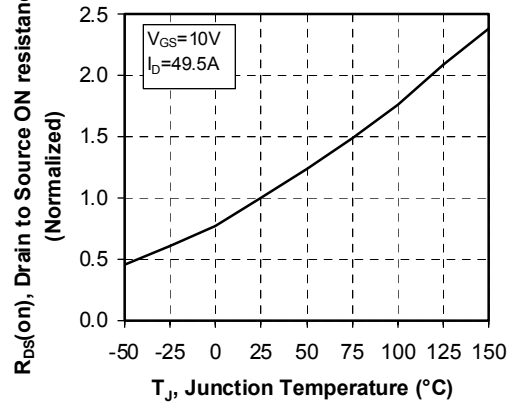
Typical Performance Curve



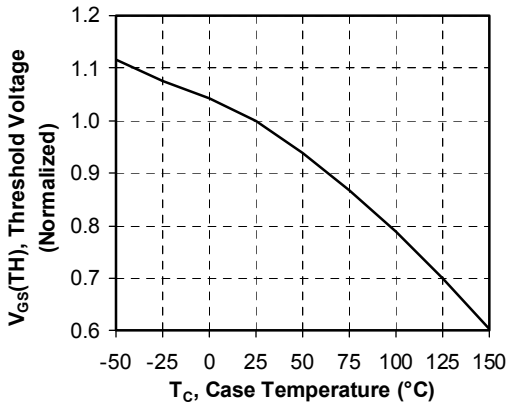
Breakdown Voltage vs Temperature



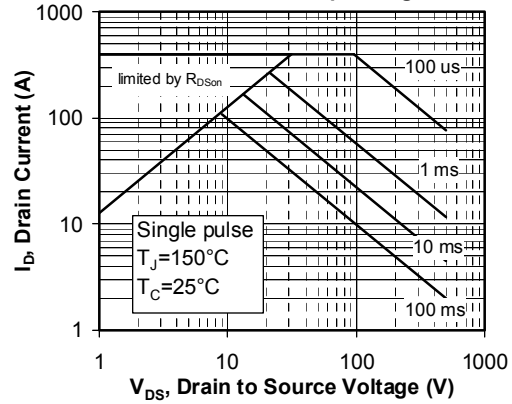
ON resistance vs Temperature



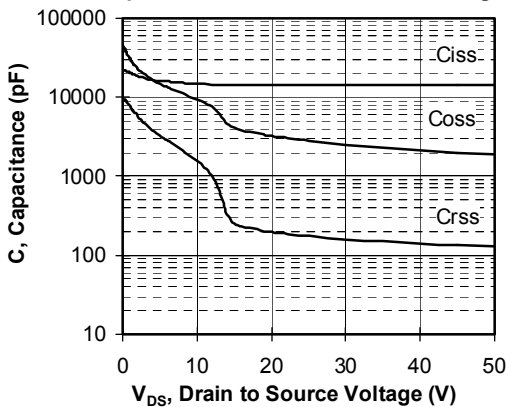
Threshold Voltage vs Temperature



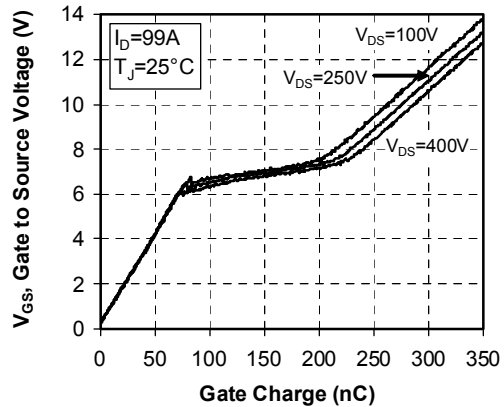
Maximum Safe Operating Area

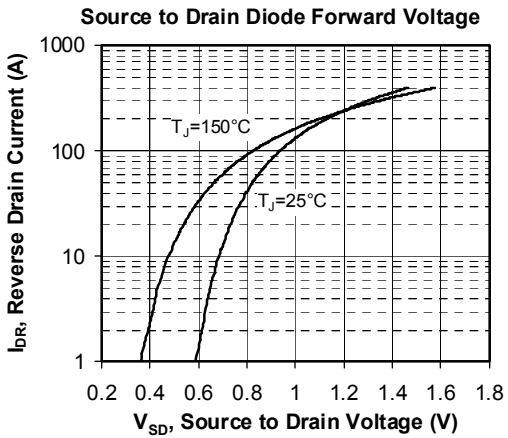
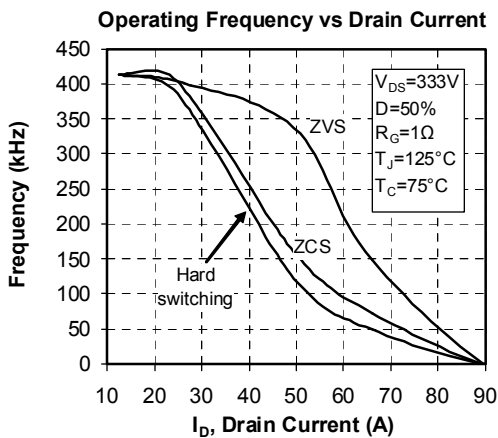
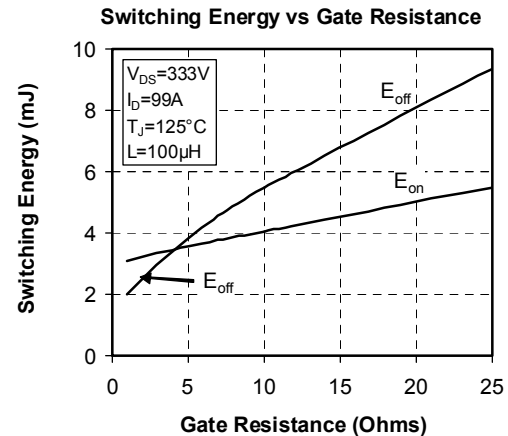
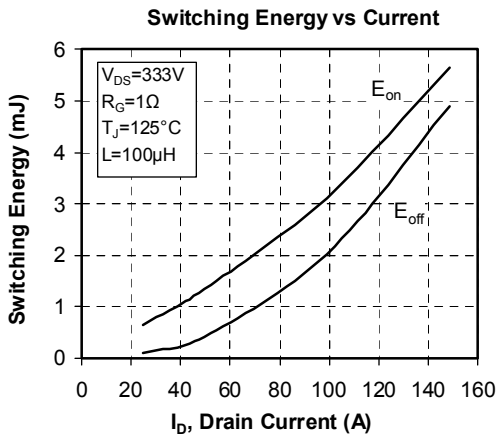
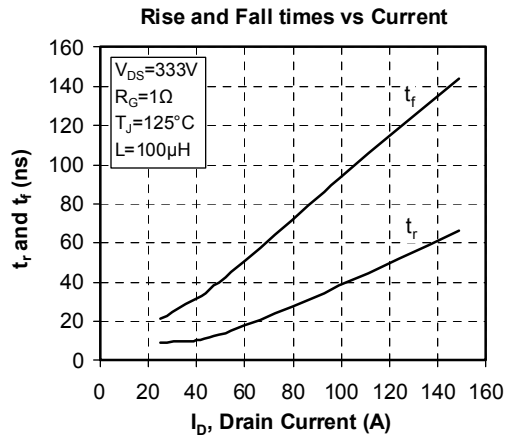
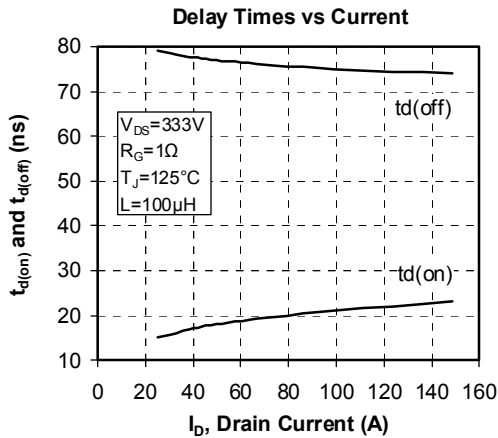


Capacitance vs Drain to Source Voltage



Gate Charge vs Gate to Source Voltage





Microsemi reserves the right to change, without notice, the specifications and information contained herein

Microsemi's products are covered by one or more of U.S. patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522 5,262,336 6,503,786 5,256,583 4,748,103 5,283,202 5,231,474 5,434,095 5,528,058 and foreign patents. U.S. and Foreign patents pending. All Rights Reserved.